

Vishay Siliconix

N-Channel 20-V (D-S) 175°C MOSFET

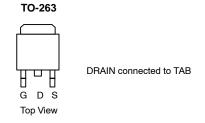
PRODUCT SUMMARY					
V _{(BR)DSS} (V)	$r_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ)		
20	0.012 @ V _{GS} = 10 V	40 ^a	7.5		
	0.026 @ V _{GS} = 4.5 V	40 ^a	7.5		

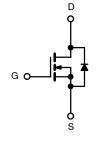
FEATURES

- TrenchFET® Power MOSFET
- 175°C Junction Temperature
- Optimized for High-Side Synchronous Rectifier
- 100% R_g Tested

APPLICATIONS

- Desktop or Server CPU Core
- Game Station





N-Channel MOSFET

Ordering Information: SUM40N02-12P SUM40N02-12P—E3

ABSOLUTE MAXIMUM RATINGS (T _A = 25°C UNLESS OTHERWISE NOTED)				
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	20	
Gate-Source Voltage		V _{GS}	±20	V
Continuous Drain Current (T _J = 175°C)	T _C = 25°C	1_	40 ^a	
	T _C = 100°C	ID	40 ^a	Α
Pulsed Drain Current		I _{DM}	90	
Maximum Power Dissipation ^b	T _C = 25°C	-	83 ^c	
	T _A = 25°C ^d	P _D	3.75	w
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to 175	°C

THERMAL RESISTANCE RATINGS					
Parameter	Symbol	Limit	Unit		
Junction-to-Ambient (PCB Mounted) ^d	R _{thJA}	40	°C/W		
Junction-to-Case	R _{thJC}	1.8			

Notes

- b.
- es
 Package limited.
 Duty cycle ≤ 1%.
 See SOA curve for voltage derating.
 When mounted on 1" square PCB (FR-4 material).

SUM40N02-12P

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Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Static	<u> </u>			I	l .	l
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{DS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V
Gate-Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS},I_D=250\;\mu A$	0.85	2	3	
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
		$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125^{\circ}\text{C}$			50	
_		V_{DS} = 20 V, V_{GS} = 0 V, T_{J} = 175°C			250	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α
		$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		0.0095	0.012	Ω
		V_{GS} = 10 V, I_D = 20 A, T_J = 125°C			0.0175	
Drain-Source On-State Resistance ^a	r _{DS(on)}	V_{GS} = 10 V, I_D = 20 A, T_J = 175°C			0.022	
		V _{GS} = 4.5 V, I _D = 15 A		0.021	0.026	
Forward Transconductancea	9 _{fs}	$V_{DS} = 15 \text{ V}, I_{D} = 20 \text{ A}$	10			S
Dynamic ^b	- 1				ľ	•
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 10 V, f = 1 MHz		1000		pF
Output Capacitance	C _{oss}			370		
Reverse Transfer Capacitance	C _{rss}			180		
Total Gate Charge ^b	Qg			7.5	12	nC
Gate-Source Charge ^b	Q _{gs}	V_{DS} = 10 V, V_{GS} = 4.5 V, I_D = 40 A		3.5		
Gate-Drain Charge ^b	Q _{gd}			2.6		
Gate Resistance	R_g		1.5	3.0	5.1	Ω
Turn-On Delay Time ^b	t _{d(on)}			11	20	ns
Rise Time ^b	t _r	$V_{DD} = 10 \text{ V, R}_{1} = 0.25 \Omega$		10	15	
Turn-Off Delay Time ^b	t _{d(off)}	V_{DD} = 10 V, R_L = 0.25 Ω I_D \cong 40 A, V_{GEN} = 10 V, R_g = 2.5 Ω		24	35	
Fall Time ^b	t _f			9	15	
Source-Drain Diode Ratings an	d Characteristics	s (T _C = 25°C) ^c				
Continuous Current	Is				40	
Pulsed Current	I _{SM}				90	A
Forward Voltage ^a	V _{SD}	$I_F = 40 \text{ A}, V_{GS} = 0 \text{ V}$		1.1	1.5	V
Reverse Recovery Time	t _{rr}			20	40	ns
Peak Reverse Recovery Current	I _{RM}	l _F = 40 A, di/dt = 100 A/μs		0.7	1.1	Α
Reverse Recovery Charge	Q _{rr}			0.007	0.022	μC

Notes

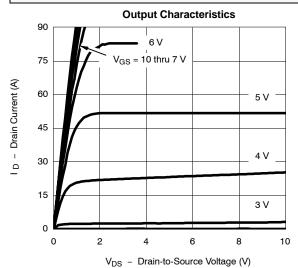
- Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2%. Independent of operating temperature. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



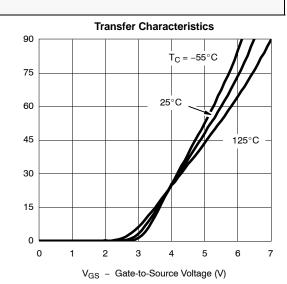


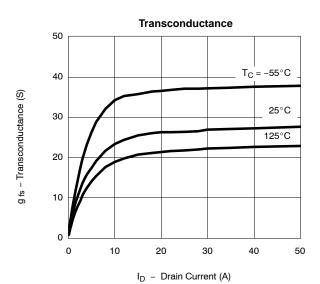
TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

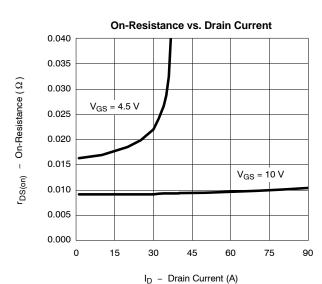


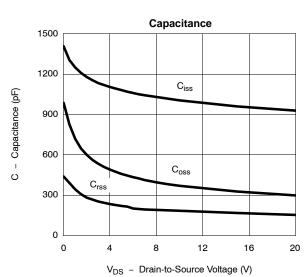


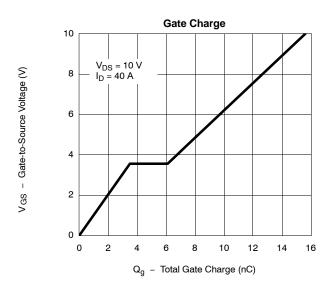
I D - Drain Current (A)







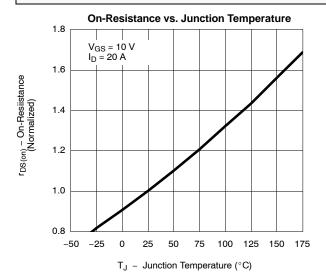


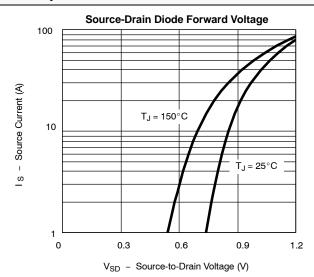


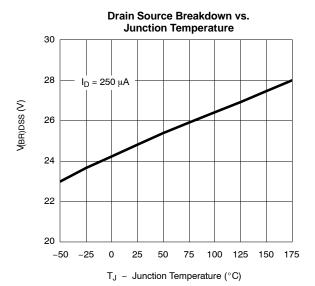
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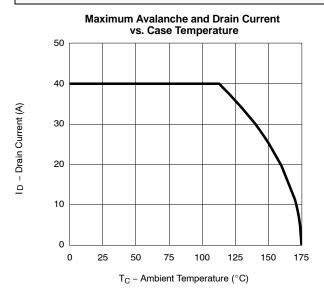


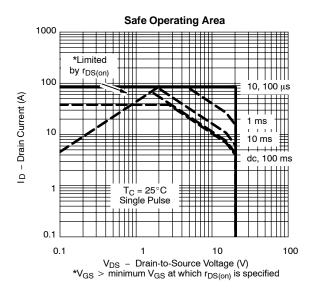


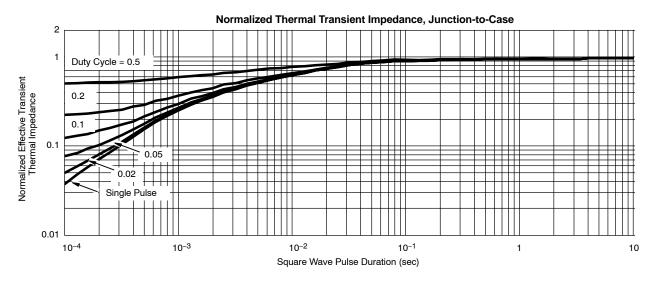


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THERMAL RATINGS







Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see http://www.vishay.com/ppg?72111.



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